TEXAS INSTRUMENTS

Data sheet acquired from Harris Semiconductor
SCHS068

CD4503B Types

CMOS Hex Buffer

High-Voltage Types (20-Volt Rating)

3-State Non-Inverting Type

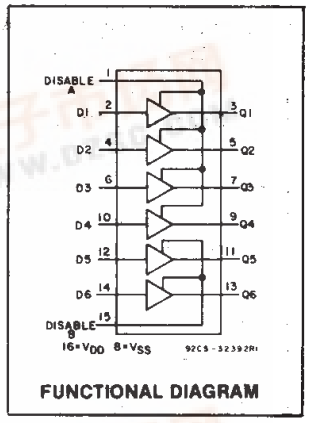
■ CD4503B is a hex noninverting buffer with 3-state outputs having high sink- and source-current capability. Two disable controls are provided, one of which controls four buffers and the other controls the remaining two buffers. The CD4503B types are supplied in 16-lead hermetic dual-in-line ceramic packages (D and F suffixes), 16-lead dual-in-line plastic packages (E suffix), and in chip form (H suffix).

Features:

- 1 TTL-load output drive capability
- 2 output-disable controls
- 3-state outputs
- Pin compatible with industry types MM80C97, MC14503, and 340097
- 5-V, 10-V, and 15-V parametric ratings
- Maximum input current of 1 μA at 18 V over full package-temperature range; 100 nA at 18 V and 25°C
- Meets all requirements of JEDEC Tentative Standard No. 13B, "Standard Specifications for Description of 'B' Series CMOS Devices"

Applications:

- 3-state hex buffer for interfacing IC's with data buses
- CMOS to TTL hex buffer



FUNCTIONAL DIAGRAM

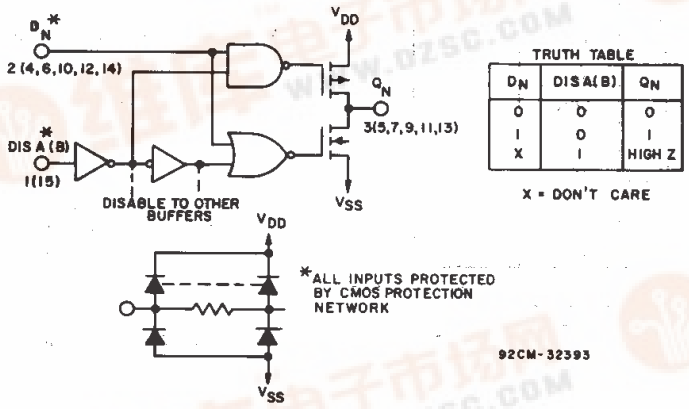


Fig. 1—Logic diagram of 1 to 6 identical buffers.

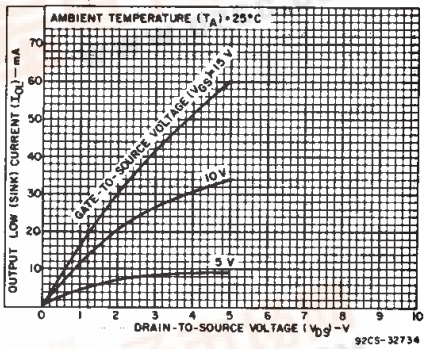


Fig. 2—Typical n-channel output low (sink) current characteristics.

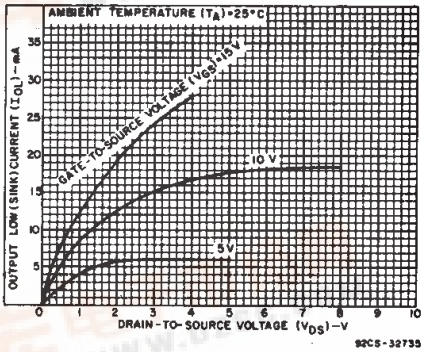
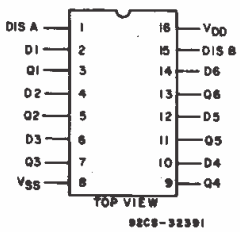


Fig. 3—Minimum n-channel output low (sink) current characteristics.

MAXIMUM RATINGS, ***Absolute-Maximum Values:***

DC SUPPLY-VOLTAGE RANGE, (V_{DD})
(Voltages referenced to V_{SS} Terminal) ..... -0.5V to +20V
INPUT VOLTAGE RANGE, ALL INPUTS ..... -0.5V to V_{DD} +0.5V
DC INPUT CURRENT, ANY ONE INPUT ..... ±10mA
POWER DISSIPATION PER PACKAGE (P_D):
For T_A = -55°C to +100°C 500mW
For T_A = +100°C to +125°C ..... Derate Linearity at 12mW/°C to 200mW
DEVICE DISSIPATION PER OUTPUT TRANSISTOR
FOR T_A = FULL PACKAGE-TEMPERATURE RANGE (All Package Types) 100mW
OPERATING-TEMPERATURE RANGE (T_A) ..... -55°C to +125°C
STORAGE TEMPERATURE RANGE (T_{stg}) ..... -65°C to +150°C
LEAD TEMPERATURE (DURING SOLDERING):
At distance 1/16 ± 1/32 inch (1.59 ± 0.79mm) from case for 10s max ..... +265°C



TERMINAL ASSIGNMENT

STATIC ELECTRICAL CHARACTERISTICS

CHARACTERISTIC	CONDITIONS			LIMITS AT INDICATED TEMPERATURES (°C)							UNITS
	V_O (V)	V_{IN} (V)	V_{DD} (V)	−55	−40	+85	+125	+25 Min.	+25 Typ.	+25 Max.	
Quiescent Device Current, I_{DD} Max.	—	0,5	5	1	1	30	30	—	0.02	1	μA
	—	0,10	10	2	2	60	60	—	0.02	2	
	—	0,15	15	4	4	120	120	—	0.02	4	
	—	0,20	20	20	20	600	600	—	0.04	20	
Output Low (Sink) Current I_{OL} Min.	0.4	0	5	2.6	2.5	1.4	1.3	2.1	2.3	—	mA
	0.5	0	10	6.5	6.4	3.9	3.8	5.5	6.2	—	
	1.5	0	15	19.2	18.9	11.4	11.2	16.1	23	—	
Output High (Source) Current, I_{OH} Min.	4.6	5	5	−1.2	−1.16	−0.7	−0.7	−1.02	−1.9	—	
	2.5	5	5	−5.8	−5.7	−3.4	−3	−4.8	−6.1	—	
	9.5	10	10	−3.1	−3	−1.9	−1.8	−2.6	−3.7	—	
	13.5	15	15	−8.2	−8	−4.9	−4.8	−6.8	−14.1	—	
Output Voltage: Low-Level, V_{OL} Max.	—	0,5	5	0.05				—	0	0.05	V
	—	0,10	10	0.05				—	0	0.05	
	—	0,15	15	0.05				—	0	0.05	
Output Voltage: High-Level, V_{OH} Min.	—	0,5	5	4.95				4.95	5	—	
	—	0,10	10	9.95				9.95	10	—	
	—	0,15	15	14.95				14.95	15	—	
Input Low Voltage, V_{IL} Max.	0.5,4.5	—	5	1.5				—	—	1.5	V
	1,9	—	10	3				—	—	3	
	1.5,13.5	—	15	4				—	—	4	
Input High Voltage, V_{IH} Min.	0.5,4.5	—	5	3.5				3.5	—	—	
	1,9	—	10	7				7	—	—	
	1.5,13.5	—	15	11				11	—	—	
Input Current I_{IN} Max.	—	0,18	18	±0.1	±0.1	±1	±1	—	$\pm 10^{-5}$	±0.1	μA
3-State Output Leakage Current, I_{OUT} Max.	0,18	0,18	18	±0.4	±0.4	±12	±12	—	$\pm 10^{-4}$	±0.4	

RECOMMENDED OPERATING CONDITIONS

For maximum reliability, nominal operating conditions should be selected so that operation is always within the following ranges:

CHARACTERISTIC	LIMITS		UNITS
	Min.	Max.	
Supply-Voltage Range (For T_A = Full Package-Temperature Range)	3	18	V

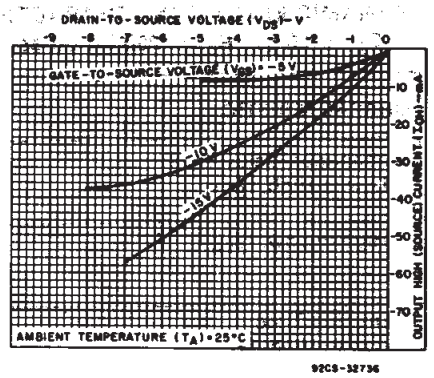


Fig. 4—Typical p-channel output high (source) current characteristics.

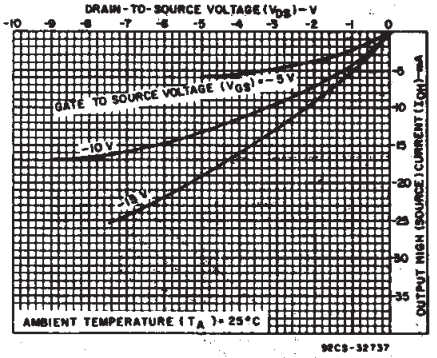


Fig. 5—Minimum p-channel output high (source) current characteristics.

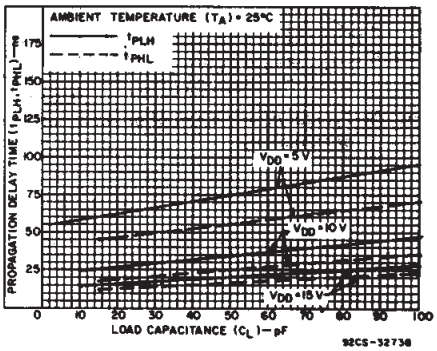


Fig. 6—Typical propagation delay time as a function of load capacitance.

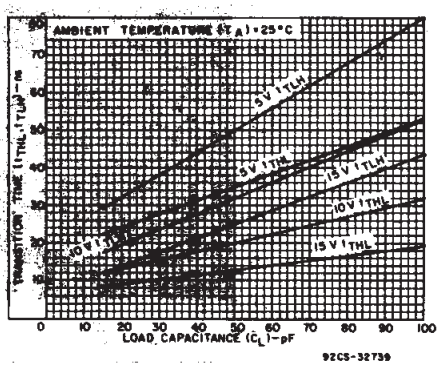


Fig. 7—Typical transition time as a function of load capacitance.

DYNAMIC ELECTRICAL CHARACTERISTICS at T_A = 25°C; Input t_r, t_f = 20 ns, C_L = 50 pF, R_L = 200 kΩ unless otherwise specified.

CHARACTERISTIC	V_{DD} (V)	LIMITS Typ.	LIMITS Max.	UNITS
Propagation Delay Time: Low-to-High, t_{PLH}	5	75	150	ns
	10	35	70	
	15	25	50	
High-to-Low, t_{PHL}	5	55	110	ns
	10	25	50	
	15	17	35	
Transition Time: Low-to-High, t_{TLH}	5	50	90	ns
	10	30	45	
	15	25	35	
High-to-Low, t_{THL}	5	35	70	ns
	10	20	40	
	15	13	25	
3-State Propagation Delay Time: R_L = 1 kΩ t_{PHZ}, t_{PZH}	5	70	140	ns
	10	30	60	
	15	25	50	
t_{PZL}, t_{PLZ}	5	90	180	ns
	10	40	80	
	15	35	70	

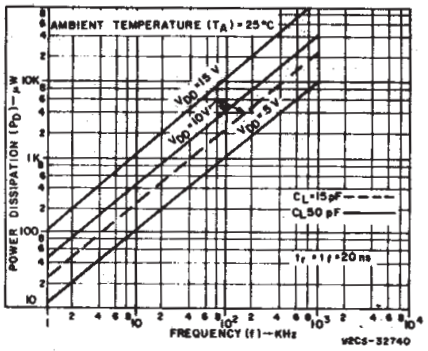


Fig. 8—Typical power dissipation as a function of frequency.

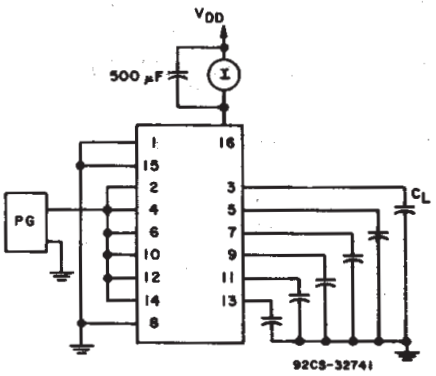


Fig. 9—Dynamic power dissipation test circuit.

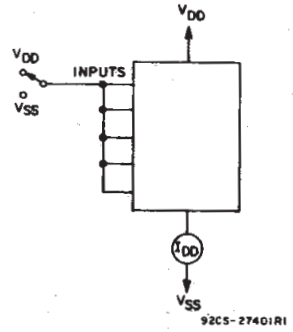


Fig. 10—Quiescent-device-current test circuit.

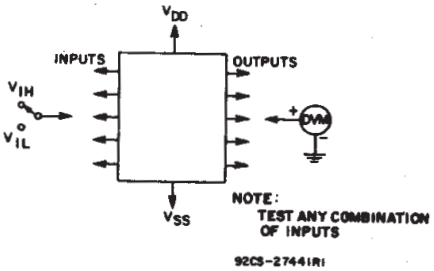


Fig. 11—Input-voltage test circuit.

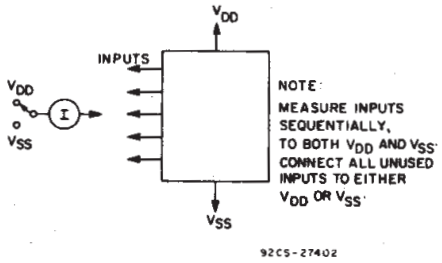
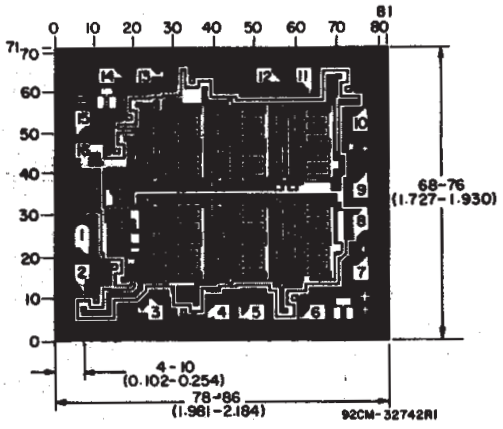


Fig. 12—Input current test circuit.



Dimensions and pad layout for CD4503BH

Dimensions in parentheses are in millimeters and are derived from the basic inch dimensions as indicated. Grid graduations are in mils (10^{-3} inch).

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